



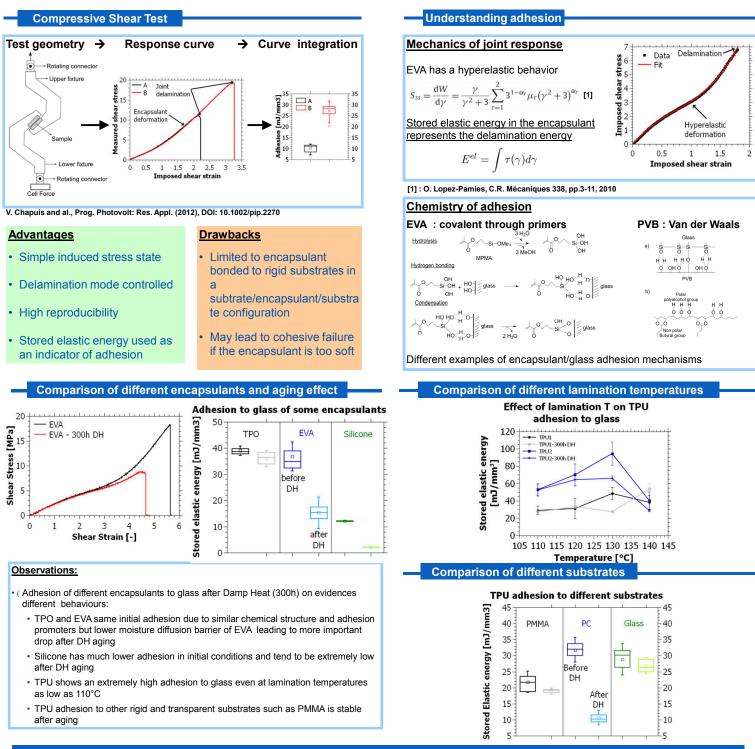
Compressive shear test to accurately measure adhesion of PV encapsulants

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Motivations and goals

- Good adhesion of PV encapsulants to glass or other module materials is needed to guarantee long lifetime
- Deep understanding of the adhesion test is needed to ensure reliable data collection



Conclusions)

- (Compressive shear test allows reproducible and reliable adhesion measurement for PV encapsulants bonded to rigid substrates
- (Testing different encapsulants allows a clear ranking in adhesion before and after aging (i.e. on glass TPO>EVA>Silicone)
- (Process tuning to optimize adhesion is straightforward (i.e. glass/TPU adhesion optimization)